

# **Dual N-Channel 12-V (D-S) MOSFET**

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω) TYP.	I <sub>D</sub> (A) a	Q <sub>g</sub> (TYP.)			
12	$0.0021$ at $V_{GS} = 4.5V$	26	31 nC			
	0.0032 at V <sub>GS</sub> = 2.5 V	22	31110			

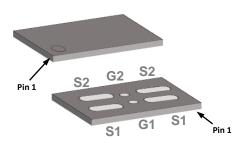
#### **FEATURES**

- DT-Trench Power MOSFET
- 100 % R<sub>a</sub> and UIS tested
- ESD Protection Diode Embedded

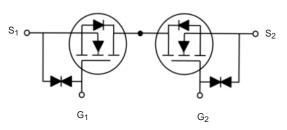


#### **APPLICATIONS**

- Battery Management
- POL Applications
- Battery Protection Applications



CSP-6 Dual Pin Configuration



N-Channel MOSFET

N-Channel MOSFET

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	12	V		
Gate-Source Voltage		V <sub>GS</sub>	±8	¬	
	T <sub>C</sub> = 25 °C		26		
Continuous Drain Current /T 150 °C\	T <sub>C</sub> = 70 °C		19		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	9.0 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		5.4 b, c	_	
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub>	105	A	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C		26		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	5.2 b, c		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	25		
Single Pulse Avalanche Energy	L = U.1 IIIII	E <sub>AS</sub>	8.9	mJ	
	T <sub>C</sub> = 25 °C		16		
Maximum Dayyar Dissination	T <sub>C</sub> = 70 °C		10.2	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.1 b, c	vv	
	T <sub>A</sub> = 70 °C		1.3 <sup>b, c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	00	
Soldering Recommendations (Peak Temperatur		260	~°C		

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum Junction-to-Ambient b, f	t ≤ 10 s	$R_{thJA}$	50	59.5	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	6	7.8	]		

#### Notes

- a. Based on  $T_C$  = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. The CSP-6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



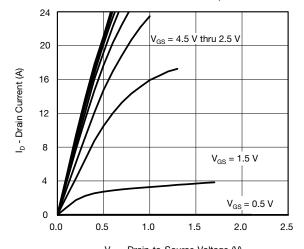


PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	12	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	20	-	mV/°	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu A$	-	-4.6	-	С	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.4	-	1.4	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$	-	-	± 10	μΑ	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 12 V ,V <sub>GS</sub> = 0 V	-	-	1		
		V <sub>DS</sub> = 10 V ,V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C	-	-	10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	26	-	-	Α	
Durin On the Oracle Business 2		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 6 A	-	0.0021	0.0028	Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 2.5 \text{ V}, I_D = 6A$	-	0.0032	0.0059		
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>		-	3050	-	- pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 6 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1010	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	603	-		
Total Gate Charge	Qg		-	39	-	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 6 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 6 \text{ A}$	-	5	-		
Gate-Drain Charge	Q <sub>gd</sub>		-	9	-		
Gate Resistance	Rg	f = 1 MHz	-	1.60	-	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		-	29	-		
Rise Time	t <sub>r</sub>	$V_{DD} = 6 \text{ V}, R_1 = 1.5 \Omega$	-	13	-	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 6 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1\Omega$	-	180	-		
Fall Time	t <sub>f</sub>		-	68	-		
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	-	-	26	A	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>		-	-	105		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 3 A	-	0.70	1.2	V	

- a. Pulse test; pulse width  $\leq\!300~\mu\text{s},$  duty cycle  $\leq\!2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c.  $T_{CASE} = 25$  °C. Expected voltage stress during 100 % UIS test. Production datalog is not available.

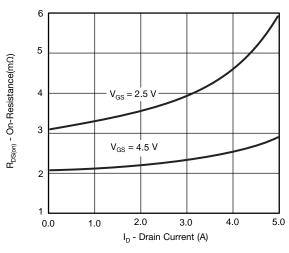
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



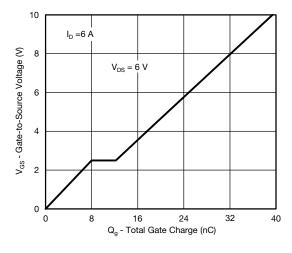


 $\mathbf{V}_{\mathrm{DS}}$  - Drain-to-Source Voltage (V)

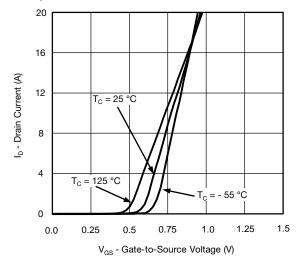




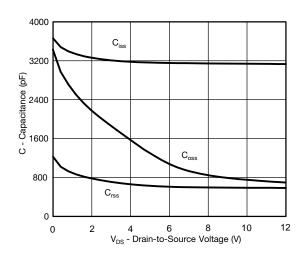
On-Resistance vs. Drain Current



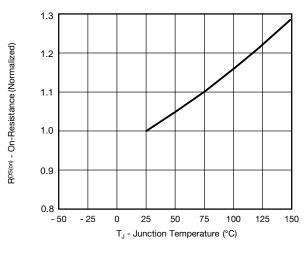
**Gate Charge** 



**Transfer Characteristics** 

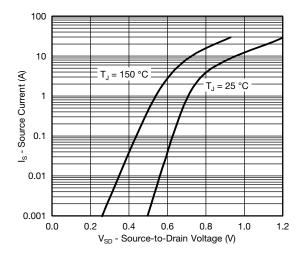


Capacitance

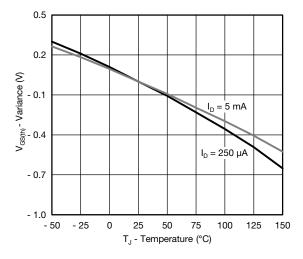


On-Resistance vs. Junction Temperature

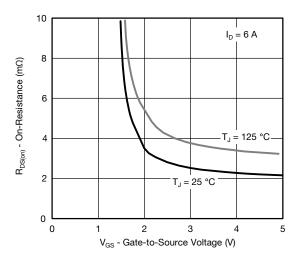




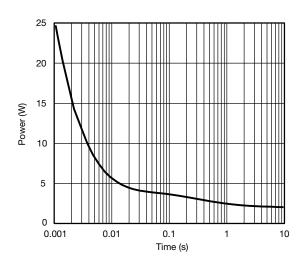
Source-Drain Diode Forward Voltage



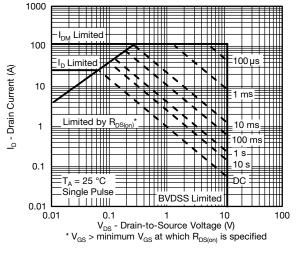
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage



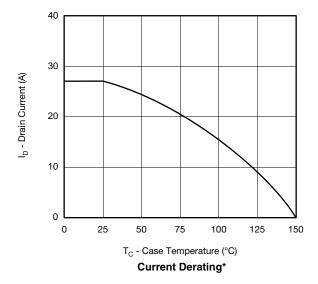
Single Pulse Power, Junction-to-Ambient

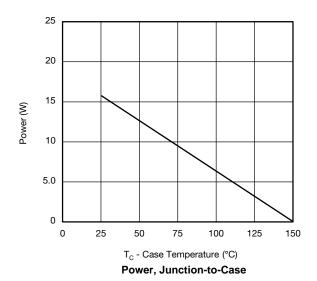


Safe Operating Area



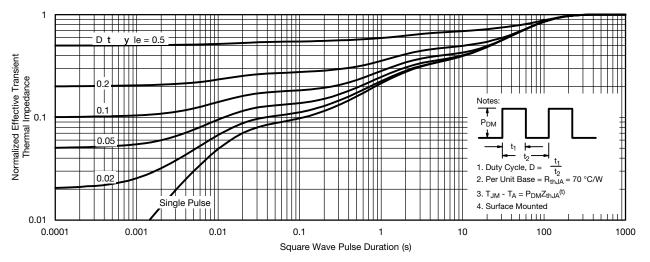




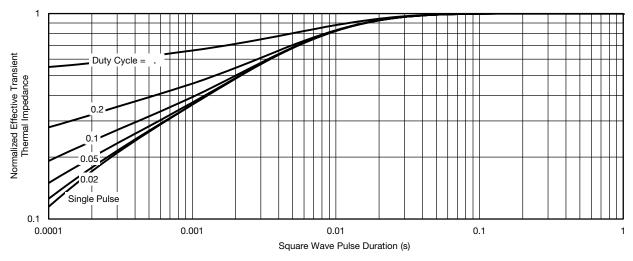


<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case





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